

Notice of References Cited

Application/Control No.

10/060,945

Applicant(s)/Patent Under
Reexamination
CARRICK ET AL.

Examiner

David S. Kim

Art Unit

2613

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	So, V.C.Y. et al. "Measuring chromatic dispersion and modal interference with an optical time-domain reflectometer." Optical Engineering. 01 September 1993, Volume 32, Issue 9: 2110-2113.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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